

## Opleidingsprogramma TOFD (Time of Flight Diffraction)

Het opleidingsprogramma dient de kandidaat voor te bereiden voor de examens. Voor kandidaten niveau 3 wordt er tevens vanuit gegaan dat deze tevens de kennis bezitten van de hieronder aangevinkte onderwerpen bij niveau 2. De totale minimale cursus duur is vermeld in de Hobéon SKO Regelingen SKNDO (par. 6).

| structure ISO/TS 25107:2019                                                                          |                                                                                                                   |                                                                                                          | TOPICS  |         |
|------------------------------------------------------------------------------------------------------|-------------------------------------------------------------------------------------------------------------------|----------------------------------------------------------------------------------------------------------|---------|---------|
| Content                                                                                              |                                                                                                                   |                                                                                                          | Level 2 | Level 3 |
| 15.1.1<br>Introduction to terminology and history of ultrasonic time-of-flight diffraction (UT-TOFD) | History                                                                                                           |                                                                                                          | X       | X       |
|                                                                                                      | Introduction to ultrasonic time-of-flight diffraction technique                                                   | Overview                                                                                                 | X       | X       |
|                                                                                                      |                                                                                                                   |                                                                                                          | X       | X       |
| 15.1.2<br>Physical principles and associated knowledge                                               | Mathematical and physical basics                                                                                  | Basics of sound beam                                                                                     | X       |         |
|                                                                                                      |                                                                                                                   | Waves                                                                                                    | X       |         |
|                                                                                                      |                                                                                                                   | — Sinusoidal movement                                                                                    | X       |         |
|                                                                                                      |                                                                                                                   | — Amplitude                                                                                              | X       |         |
|                                                                                                      |                                                                                                                   | — Frequency                                                                                              | X       |         |
|                                                                                                      |                                                                                                                   | — Wavelength                                                                                             | X       |         |
|                                                                                                      |                                                                                                                   | — Propagation velocity                                                                                   | X       |         |
|                                                                                                      |                                                                                                                   | — Longitudinal waves                                                                                     | X       |         |
|                                                                                                      |                                                                                                                   | — Transverse waves                                                                                       | X       |         |
|                                                                                                      |                                                                                                                   | Principle of wave-diffraction                                                                            | X       | X       |
|                                                                                                      |                                                                                                                   | Sound-field of UT-TOFD probes                                                                            | X       | X       |
|                                                                                                      |                                                                                                                   | Visualization of UT-TOFD images                                                                          | X       | X       |
|                                                                                                      |                                                                                                                   | Probe centre separation (PCS)                                                                            | X       | X       |
| 15.1.3<br>Product knowledge and related capability of the method and derived techniques              | Various defects related to the manufacturing processes and service-induced defects related to the defined sectors | Defects related to the manufacturing processes (welding)                                                 | X       |         |
|                                                                                                      |                                                                                                                   | Implementation of UT-TOFD technique according to products and to expected discontinuities (weld defects) | X       |         |
|                                                                                                      | Overall properties of specimen                                                                                    | Influence of surface conditions                                                                          | X       | X       |
|                                                                                                      |                                                                                                                   | Geometry                                                                                                 | X       | X       |
|                                                                                                      |                                                                                                                   | Attenuation                                                                                              | X       | X       |
|                                                                                                      |                                                                                                                   | Reference reflectors (SDH), notch                                                                        | X       | X       |
|                                                                                                      | Test instrument and combined equipment                                                                            | UT-TOFD instrument                                                                                       | X       | X       |
|                                                                                                      |                                                                                                                   | UT-TOFD probes                                                                                           | X       | X       |

|                                     |                                      |                                                                     |          |          |
|-------------------------------------|--------------------------------------|---------------------------------------------------------------------|----------|----------|
|                                     |                                      | Adaption of probes to curved scanning surfaces                      | <b>X</b> | <b>X</b> |
|                                     |                                      | Encoders and scanning mechanisms                                    | <b>X</b> | <b>X</b> |
|                                     |                                      | Different types of scanners                                         | <b>X</b> | <b>X</b> |
|                                     |                                      | Reference blocks                                                    | <b>X</b> | <b>X</b> |
|                                     |                                      | Different reference blocks                                          | <b>X</b> | <b>X</b> |
| 15.1.5<br>Information prior to test | Items to be defined by specification | Purpose                                                             | <b>X</b> |          |
|                                     |                                      | Extent of UT-TOFD testing                                           | <b>X</b> |          |
|                                     |                                      | Information required by the operator                                | <b>X</b> |          |
|                                     |                                      | Written test instruction or procedure                               | <b>X</b> |          |
| 15.1.6<br>Testing                   |                                      | Setting of test range and sensitivity                               | <b>X</b> |          |
|                                     |                                      | Setup of probes                                                     | <b>X</b> | <b>X</b> |
|                                     |                                      | — Scan increment setting                                            | <b>X</b> | <b>X</b> |
|                                     |                                      | — Geometry considerations                                           | <b>X</b> | <b>X</b> |
|                                     |                                      | — Preparation of scanning surfaces                                  | <b>X</b> | <b>X</b> |
|                                     |                                      | — Couplant and coupling techniques                                  | <b>X</b> | <b>X</b> |
|                                     |                                      | Range and sensitivity settings                                      | <b>X</b> | <b>X</b> |
|                                     |                                      | — Time window                                                       | <b>X</b> | <b>X</b> |
|                                     |                                      | — Time-to-depth conversion                                          | <b>X</b> | <b>X</b> |
|                                     |                                      | — Sensitivity settings                                              | <b>X</b> | <b>X</b> |
|                                     |                                      | — Checking of settings                                              | <b>X</b> | <b>X</b> |
|                                     |                                      | Reference blocks                                                    | <b>X</b> | <b>X</b> |
|                                     |                                      | — Material                                                          | <b>X</b> | <b>X</b> |
|                                     |                                      | — Dimensions                                                        | <b>X</b> | <b>X</b> |
|                                     |                                      | — Shape                                                             | <b>X</b> | <b>X</b> |
|                                     |                                      | — Reference reflectors, SDH and notch                               | <b>X</b> | <b>X</b> |
|                                     |                                      | Interpretation and analysis of UT-TOFD images                       | <b>X</b> | <b>X</b> |
|                                     |                                      | — Assessing the quality of the UT-TOFD image                        | <b>X</b> | <b>X</b> |
|                                     |                                      | — Identification and classification of relevant UT-TOFD indications | <b>X</b> | <b>X</b> |

|                                    |                         |                                                                                     |          |          |
|------------------------------------|-------------------------|-------------------------------------------------------------------------------------|----------|----------|
|                                    |                         | — Determination of location and size                                                | <b>X</b> | <b>X</b> |
| 15.1.7<br>Evaluation and reporting |                         | Evaluation according to acceptance criteria                                         | <b>X</b> |          |
|                                    |                         | Test report                                                                         | <b>X</b> |          |
|                                    |                         | — Information relating to the test object                                           | <b>X</b> |          |
|                                    |                         | — Equipment                                                                         | <b>X</b> |          |
|                                    |                         | — Test technique                                                                    | <b>X</b> |          |
|                                    |                         | — Test results                                                                      | <b>X</b> |          |
|                                    |                         | Storage of data-files                                                               | <b>X</b> |          |
|                                    |                         | Generation of reports                                                               | <b>X</b> |          |
|                                    |                         | Near surface and opposite surface resolution                                        | <b>X</b> | <b>X</b> |
|                                    |                         | Defect location and length measurement                                              | <b>X</b> | <b>X</b> |
| 15.1.8<br>Assessment               |                         | Evaluation and confirmation of test reports                                         | <b>X</b> |          |
|                                    |                         | Application of the acceptance criteria according to standards, codes and procedures | <b>X</b> | <b>X</b> |
|                                    |                         | Offline evaluation using PC software                                                | <b>X</b> |          |
| 15.1.9<br>Quality aspects          | Personnel qualification | ISO 9712                                                                            | <b>X</b> |          |
|                                    |                         | Other NDT qualification and certification systems                                   | <b>X</b> |          |
| 15.1.10<br>Developments            | Not applicable          |                                                                                     |          | <b>X</b> |
|                                    |                         |                                                                                     |          |          |